



Artificial Intelligence in Image Reconstruction

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Message from the Guest Editors

Artificial Intelligence (AI) in Image Processing for the reconstruction of images is a highly promising area of research. The reconstruction of an image from the acquired data is an inverse problem which is often not possible to solve directly. The convergence of AI in this field can overcome certain challenges and can also increase the accuracy of the algorithms. Image reconstruction can be applied in many situations, including but not limited to, 3D shape reconstruction, texture analysis, medical imaging, and robotics.

The topics of interest in this Special Issue include, but are not limited to:

- X-ray CT image reconstruction
- MRI image reconstruction
- Medical diagnosis support systems
- Texture Analysis
- 3D Depth/Shape Recovery
- Robot Navigation Systems
- Autonomous Vehicle Navigation Systems
- Biometric and Security systems

You are welcome to contribute!!!





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Message from the Editor-in-Chief

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